

<b>Notice of References Cited</b>	Application/Control No. 09/814,522	Applicant(s)/Patent Under Reexamination YEN ET AL.	
	Examiner Yemane M Gerezgiher	Art Unit 2144	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,697,792 B2	02-2004	Bunney et al.	707/1
*	B	US-6,496,855 B1	12-2002	Hunt et al.	709/217
*	C	US-2002/0016910 A1	02-2002	Wright et al.	713/150
*	D	US-5,790,785 A	08-1998	Klug et al.	713/202
*	E	US-5,961,593	10-1999	Gabber et al.	709/219
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 200052900 A1	09-2000	World Intellect	BYRN et al.	G06F 15/00
	O	WO 200184359 A2	11-2001	World Intellect	PALNITKAR et al.	G06F 15/00
	P	WO 200180067 A1	10-2001	World Intellect	INALA et al.	G06F 15/16
	Q	JP 2001282841 A	10-2001	Japan	FUKUDA, TOSHIHIRO	G06F 17/30
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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